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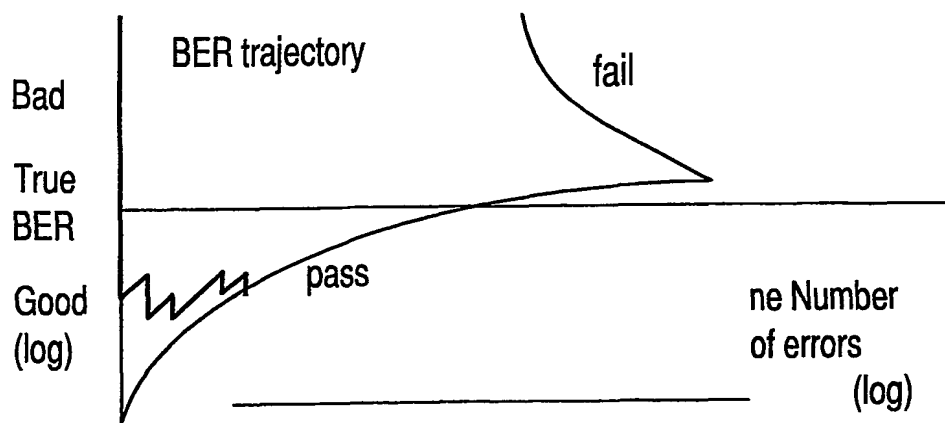
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ance Notes on Codes and Abbreviations" appearing at the begin-  
ning of each regular issue of the PCT Gazette.

(54) Title: METHOD FOR TESTING THE ERROR RATIO BER OF A DEVICE ACCORDING TO CONFIDENCE LEVEL,  
TEST TIME AND SELECTIVITY



(57) Abstract: A method for testing the error ratio BER of a device under test against a specified allowable error ratio comprises the steps: measuring  $n_s$  samples of the output of the device, thereby detecting  $n_e$  erroneous samples of these  $n_s$  samples, defining  $BER(n_e) = n_e/n_s$  as the preliminary error ratio and deciding to pass the device, if the preliminary error ratio  $BER(n_e)$  is smaller than an early pass limit  $EPL(n_e)$ . The early pass limit is constructed by using an empirically or analytically derived distribution for a specific number of devices each having the specified allowable error ratio by separating a specific portion  $DD$  of the best devices from the distribution for a specific number of erroneous samples  $n_e$  and proceeding further with the remaining part of the distribution for an incremented number of erroneous samples.